

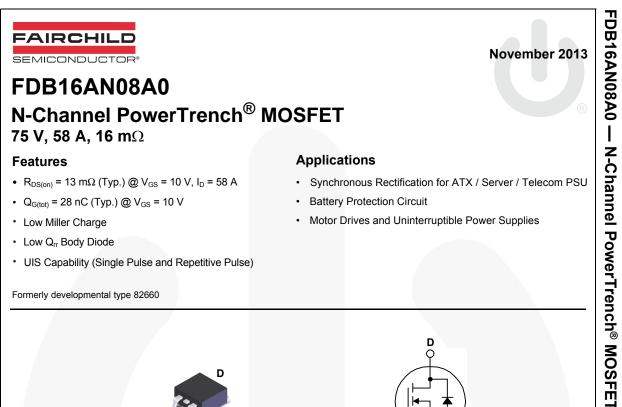
Is Now Part of

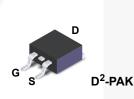


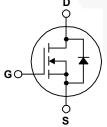
ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at <u>www.onsemi.com</u>

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor dates sheds, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor dates sheds and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use on similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor and its officers, employees, subsidiaries, affliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out or i, directly or indirectly, any lay bed ON Semiconductor and its officers, employees, ween if such claim alleges that ON Semiconductor was negligent regarding the d







MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter	FDB16AN08A0	Unit	
V _{DSS}	Drain to Source Voltage	75	V	
V _{GS}	Gate to Source Voltage	±20	V	
I _D	Drain Current			
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$)	58	А	
	Continuous ($T_C = 100^{\circ}C$, $V_{GS} = 10V$)	44		
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 43^{\circ}C/W$)	9	Α	
	Pulsed	Figure 4	A	
E _{AS}	Single Pulse Avalanche Energy (Note 1)	117	mJ	
P _D	Power dissipation	135	W	
	Derate above 25°C	0.9	W/°C	
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C	

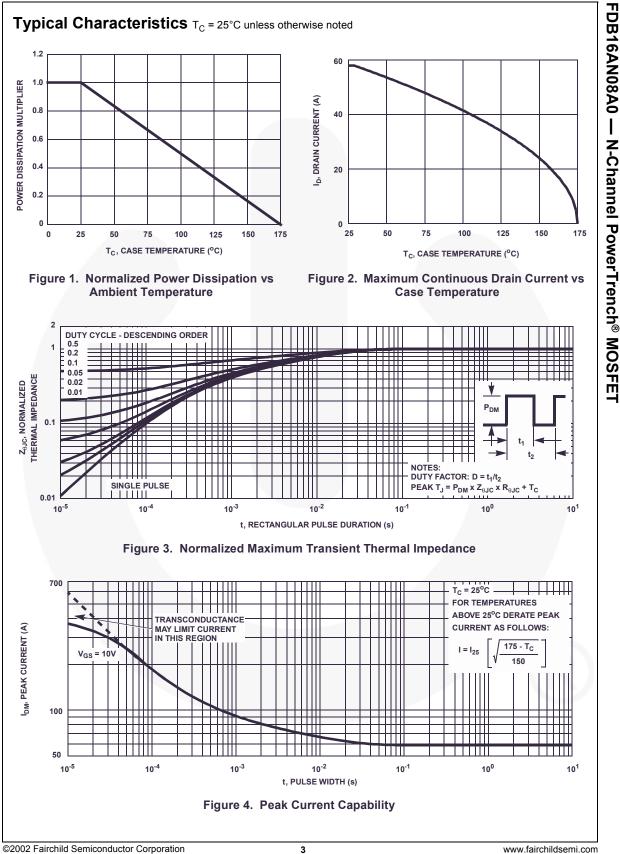
Thermal Characteristics

$R_{ extsf{ heta}JC}$	Thermal Resistance Junction to Case, Max.	1.11	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient, Max.	62	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient, 1in ² Copper Pad Area, Max.	43	°C/W

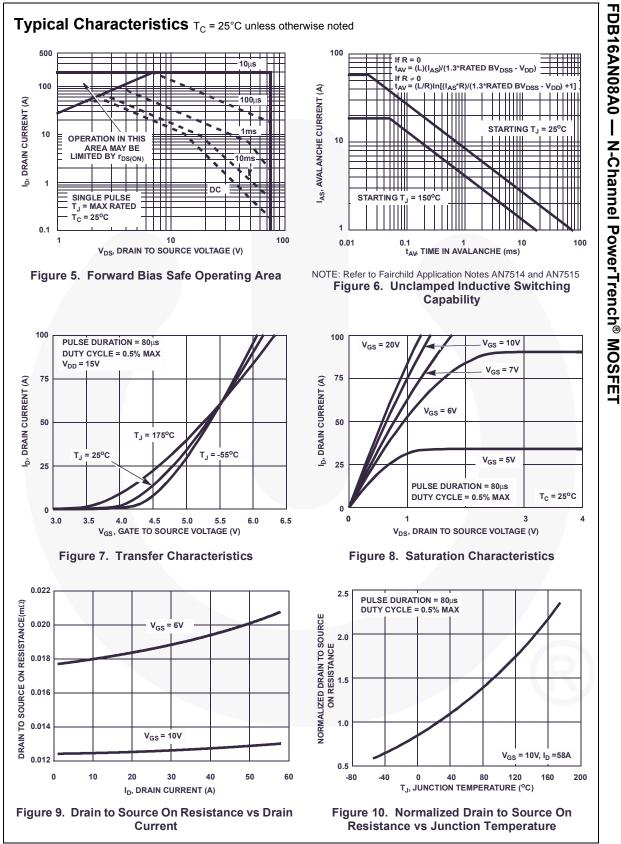
1

Device Marking FDB16AN08A0		Device	Package	Reel Size	Tape Width 24 mm		Quantity 800 units	
		FDB16AN08A0	D ² -PAK	330 mm				
Electric	al Char	racteristics T _C = 25°C	C unless otherwis	se noted.				
Symbol	Parameter		Test Conditions		Min	Тур	Max	Unit
Off Chara	ctoristic	c			-0	•		•
	1	Source Breakdown Voltage	I _D = 250μA, V	(a a = 0)/	75		_	V
B _{VDSS}			V _{DS} = 60V	GS OV	-	-	1	v
DSS Zero Gate		e Voltage Drain Current	$V_{GS} = 0V$	T _C = 150 ^o C	-		250	μA
I _{GSS}	Gate to Source Leakage Current		V _{GS} = ±20V	0	-	-	±100	nA
On Chara	cteristic	s	·					
V _{GS(TH)}		ource Threshold Voltage	V _{GS} = V _{DS} , I _E	= 250µA	2	-	4	V
• GS(1H)		called Threehold Voltage	$I_{\rm D} = 58$ A, V _{G8}		-	0.013	0.016	v
	D		$I_{\rm D} = 29$ A, V _{GS}		-	0.019	0.029	_
r _{DS(ON)}	Drain to S	Source On Resistance	$I_D = 58A, V_{GS}$ $T_1 = 175^{\circ}C$		-	0.032	0.037	Ω
Dynamic	Characte	eristics				<u> </u>	I	
C _{ISS}	Input Cap				-	1857	-	pF
C _{OSS}		apacitance	V _{DS} = 25V, V	_{GS} = 0V,	-	288	-	pF
C _{RSS}		Fransfer Capacitance	f = 1MHz		-	88	-	pF
Q _{g(TOT)}	-	e Charge at 10V	$V_{GS} = 0V$ to 1	0V		28	42	nC
Q _{g(TH)}		Gate Charge	$V_{GS} = 0V \text{ to } 2$		-	3.5	5	nC
Q _{gs}	Gate to S	ource Gate Charge		I _D = 58A	-	11	-	nC
Q _{gs2}	Gate Cha	rge Threshold to Plateau		I _g = 1.0mA	-	7.6	-	nC
Q _{gd}	Gate to D	rain "Miller" Charge	<u> </u>		-	6.4	-	nC
Switching	g Charac	teristics (V _{GS} = 10V)						
t _{ON}	Turn-On T	Гime			-	-	135	ns
t _{d(ON)}	Turn-On E	Delay Time				8	-	ns
t _r	Rise Time	9	V _{DD} = 40V, I _D	= 58A		82		ns
t _{d(OFF)}	Turn-Off [Delay Time	V _{GS} = 10V, F	c _{GS} = 10Ω	/ -	28	-	ns
t _f	Fall Time				-	30		ns
t _{OFF}	Turn-Off 1	Time			-	-	86	ns
Drain-Sou	urce Diod	de Characteristics						
V _{SD}	Source to	Drain Diode Voltage	I _{SD} = 58A		-	-	1.25	V
		Recovery Time	$I_{SD} = 29A$	/dt = 100 A/wc	-	-	1.0 35	V
t _{rr} Q _{RR}	-	Recovered Charge		$I_{SD} = 58A, dI_{SD}/dt = 100A/\mu s$ $I_{SD} = 58A, dI_{SD}/dt = 100A/\mu s$		-	36	ns nC
	I toverbe i	teoovered ondige		SD/41 100/140	-		00	110

FDB16AN08A0 — N-Channel PowerTrench® MOSFET

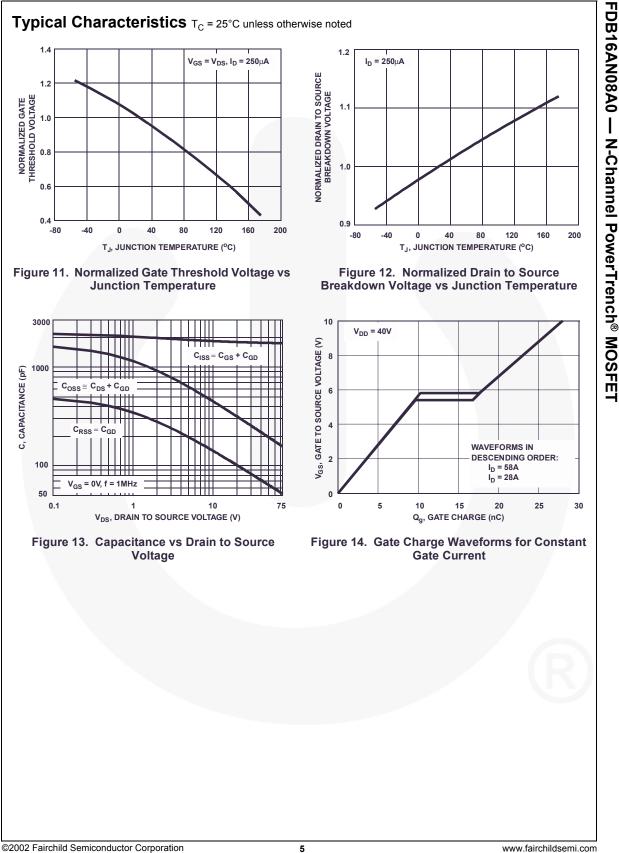


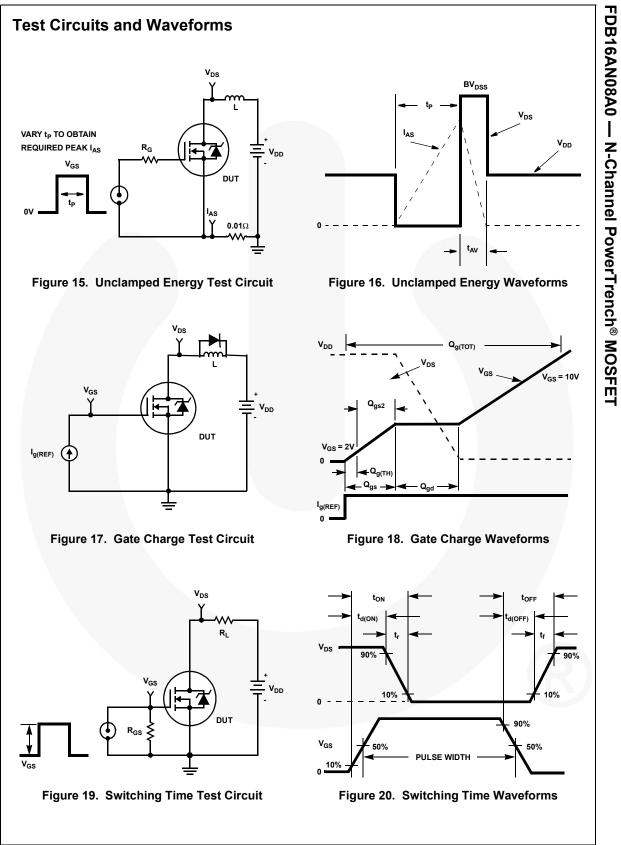
FDB16AN08A0 Rev. C2



©2002 Fairchild Semiconductor Corporation FDB16AN08A0 Rev. C2

www.fairchildsemi.com





©2002 Fairchild Semiconductor Corporation FDB16AN08A0 Rev. C2 www.fairchildsemi.com

10

(64.5)

Thermal Resistance vs. Mounting Pad Area

80

60

R_{0JA} (°C/W)

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

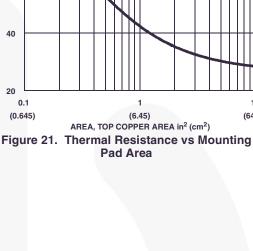
$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + Area)}$$
 (EQ. 3)

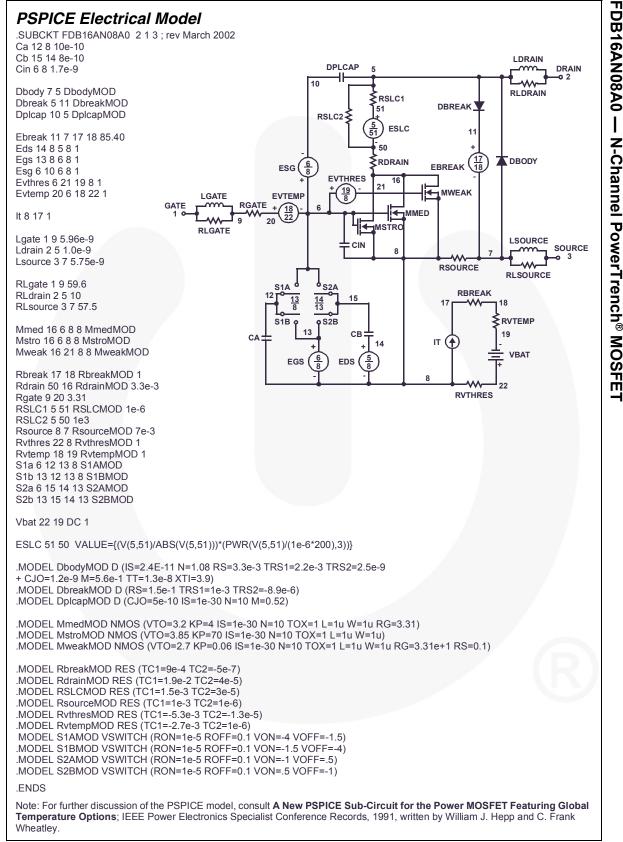
Area in Centimeters Squared

©2002 Fairchild Semiconductor Corporation FDB16AN08A0 Rev. C2



= 26.51+ 19.84/(0.262+Area) EQ.2

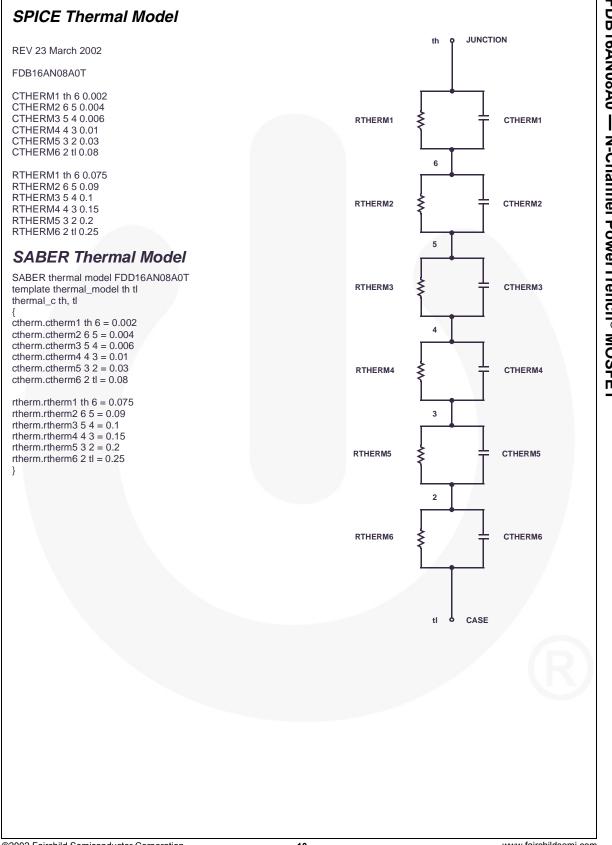
Re.14 = 26.51+ 128/(1.69+Area) EQ.3

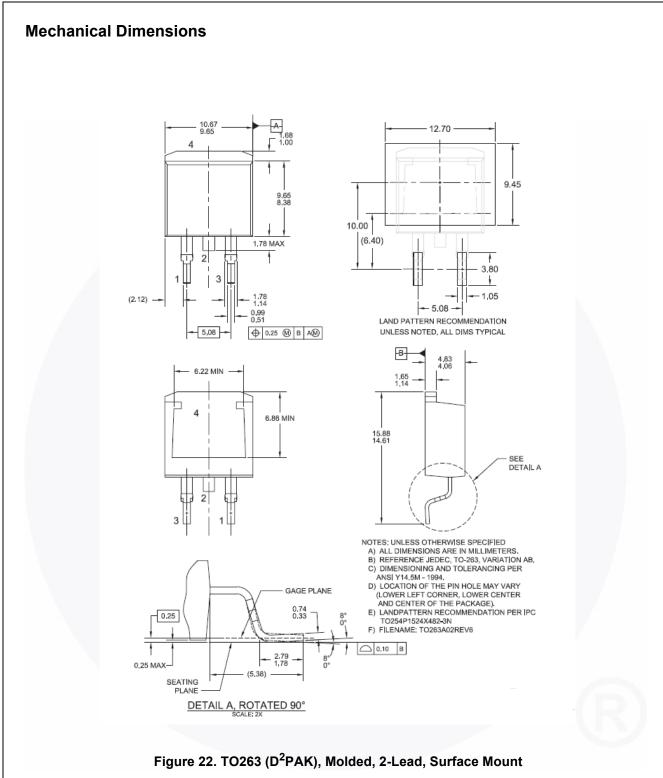


©2002 Fairchild Semiconductor Corporation FDB16AN08A0 Rev. C2

SABER Electrical Model DB16AN08A0 — N-Channel PowerTrench[®] MOSFE rev March 2002 template FDB16AN08A0 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=2.4e-11,nl=1.08,rs=3.3e-3,trs1=2.2e-3,trs2=2.5e-9,cjo=1.2e-9,m=5.6e-1,tt=1.3e-8,xti=3.9) dp..model dbreakmod = (rs=1.5e-1,trs1=1e-3,trs2=-8.9e-6) dp..model dplcapmod = (cjo=5e-10,isl=10e-30,nl=10,m=0.52)m..model mmedmod = (type=_n,vto=3.2,kp=4,is=1e-30, tox=1) m..model mstrongmod = (type=_n,vto=3.85,kp=70,is=1e-30, tox=1) m..model mweakmod = (type=_n,vto=2.7,kp=0.06,is=1e-30, tox=1,rs=0.1) I DRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-4,voff=-1.5) DPLCAP DRAIN \mathbf{m} sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-1.5,voff=-4) -02 10 sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-1,voff=.5) RLDRAIN sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=.5,voff=-1) ≰RSLC1 c.ca n12 n8 = 10e-10 51 RSLC2 ₹ c.cb n15 n14 = 8e-10 ISCL c.cin n6 n8 = 1.7e-9 DBREAK 50 dp.dbody n7 n5 = model=dbodymod RDRAIN dp.dbreak n5 n11 = model=dbreakmod 6 ESG 11 dp.dplcap n10 n5 = model=dplcapmod DBODY EVTHRES 16 21 (<u>19</u> 8 MWFAK spe.ebreak n11 n7 n17 n18 = 85.40 GATE LGATE EVTEMP RGATE ണ spe.eds n14 n8 n5 n8 = 1 18 22 EBREA 19 20 . spe.egs n13 n8 n6 n8 = 1 MSTRO RLGATE spe.esg n6 n10 n6 n8 = 1 LSOURCE spe.evthres n6 n21 n19 n8 = 1 CIN SOURCE \mathbf{m} 8 spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1 RBREAK I.lgate n1 n9 = 5.96e-9 17 \sim 18 I.ldrain n2 n5 = 1.0e-9 RVTEMP l.lsource n3 n7 = 5.75e-9 S1B S2B СВ 19 CA IT 4 14 res.rlgate n1 n9 = 59.6 VBAT res.rldrain n2 n5 = 105 EGS EDS res.rlsource n3 n7 = 57.5 8 22 m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u RVTHRES m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u res.rbreak n17 n18 = 1, tc1=9e-4,tc2=-5e-7 res.rdrain n50 n16 = 3.3e-3, tc1=1.9e-2,tc2=4e-5 res.rgate n9 n20 = 3.31 res.rslc1 n5 n51 = 1e-6, tc1=1.5e-3,tc2=3e-5 res.rslc2 n5 n50 = 1e3res.rsource n8 n7 = 7e-3, tc1=1e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-5.3e-3,tc2=-1.3e-5 res.rvtemp n18 n19 = 1, tc1=-2.7e-3,tc2=1e-6 sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/200))**3))}

9





Package drawings are provided as a service to customers considering Fairchild components. Drawings may change in any manner without notice. Please note the revision and/or date on the drawing and contact a Fairchild Semiconductor representative to verify or obtain the most recent revision. Package specifications do not expand the terms of Fairchild's worldwide terms and conditions, specifically the warranty therein, which covers Fairchild products.

Always visit Fairchild Semiconductor's online packaging area for the most recent package drawings:

http://www.fairchildsemi.com/package/packageDetails.html?id=PN_TT263-002

FDB16AN08A0 — N-Channel PowerTrench[®] MOSFET



ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <u>www.onsemi.com/site/pdf/Patent-Marking.pdf</u>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor has against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death ass

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Japan Customer Focus Center Phone: 81-3-5817-1050 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

© Semiconductor Components Industries, LLC